

1. Record Nr.	UNINA9910143127803321
Autore	Ochkin V. N (Vladimir Nikolaevich)
Titolo	Spectroscopy of low temperature plasma [[electronic resource] /] / Vladimir N. Ochkin ; [translated by Sergey Kittell]
Pubbl/distr/stampa	Weinheim, : Wiley-VCH, c2009
ISBN	1-282-13990-8 9786612139901 3-527-62750-2 3-527-62751-0
Descrizione fisica	1 online resource (633 p.)
Disciplina	530.446
Soggetti	Plasma spectroscopy Low temperature plasmas
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references and index.
Nota di contenuto	Spectroscopy of Low Temperature Plasma; Contents; Preface; 1 Plasma as an Object of Spectroscopy; 2 Basic Concepts and Parameters Associated with the Emission, Absorption and Scattering of Light by Plasma; 3 Emission, Absorption and Scattering Techniques for Determining the Densities of Particles in Discrete Energy States; 4 Intensities in Spectra and Plasma Energy Distribution in the Internal and Translational Degrees of Freedom of Atoms and Molecules; 5 Measuring Concentrations of Atoms and Molecules; 6 Spectral Methods of Determining Electronic and Magnetic Fields in Plasma 7 Determination of the Parameters of the Electronic Component of Plasma 8 Some Information on Spectroscopy Techniques; Appendix A Statistical Weights and Statistical Sums; Appendix B Conversion of Quantities Used to Describe Optical Transition Probabilities in Line Spectra; Appendix C Two-Photon Absorption Cross Sections for Some Atoms and Molecules in the Ground State; Appendix D Information on Some Diatomic Molecules for the Identification and Processing of Low-Temperature Plasma Spectra Appendix E Rotational Line Intensity Factors in the Electronic-Vibrational Transition Spectra of Diatomic Molecules Appendix F

Measurement of the Absolute Populations of Excited Atoms by Classical Spectroscopy Techniques; Appendix G General Information for Plasma Spectroscopy Problems; Index

**Sommario/riassunto**

Written by a distinguished plasma scientist and experienced author, this up-to-date work comprehensively covers current methods and new developments and techniques, including non-equilibrium atomic and molecular plasma states, as well as such new applications as gas lasers. Containing numerous appendices with reference data indispensable for plasma spectroscopy, such as statistical weights and partition sums and diatomic molecules. For plasmaphysicists, spectroscopists, materials scientists and physical chemists. Appendix H is only available online.

2. **Record Nr.**

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**Titolo**

Advances in mathematical modeling for reliability // edited by Tim Bedford ... [et al.]

**Pubbl/distr/stampa**

Amsterdam ; ; Washington, DC, : IOS Press, c2008

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**Edizione**

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**Descrizione fisica**

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**Altri autori (Persone)**

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**Disciplina**

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**Soggetti**

Engineering - Mathematical models  
Reliability (Engineering)

**Lingua di pubblicazione**

Inglese

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**Note generali**

Description based upon print version of record.

**Nota di bibliografia**

Includes bibliographical references and indexes.

**Nota di contenuto**

Title page; Introduction; Contents; Graphical Modeling and Bayesian Networks; Repairable Systems Modeling; Competing Risks; Mixture Failure Rate Modeling; Signature; Relations Among Aging and Stochastic Dependence; Theoretical Advances in Modeling, Inference and Computation; Recent Advances in Recurrent Event Modeling and Inference; Point Estimation of the Transition Intensities for a Markov Multi-State System via Output Performance Observation; Keyword Index; Author Index

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**Sommario/riassunto**

Discusses fundamental issues on mathematical modeling in reliability theory and its applications. Beginning with a discussion of graphical modeling and Bayesian networks, this work then focuses on repairable systems. It also addresses how competing risks arise in reliability and maintenance analysis through the ways in which data is censored.

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